Notice of Allowability	Application No.	Applicant(s)
	10/650,234	GUNN ET AL.
	Examiner	Art Unit
	PHAN T.H. PALMER	2874
The MAILING DATE of this communication apperall daims being allowable, PROSECUTION ON THE MERITS IS (herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIG	(OR REMAINS) CLOSED in this a or other appropriate communicati GHTS. This application is subject	application. If not included on will be mailed in due course. THIS
1. This communication is responsive to <u>07/08/2005</u> .		
2. The allowed claim(s) is/are <u>1-23,47-69 and 93-109</u> .		
3. $\square$ The drawings filed on $\_\_\_$ are accepted by the Examiner		
<ul> <li>4. Acknowledgment is made of a claim for foreign priority un</li> <li>a) All b) Some* c) None of the:</li> <li>1. Certified copies of the priority documents have</li> <li>2. Certified copies of the priority documents have</li> <li>3. Copies of the certified copies of the priority documents have</li> <li>International Bureau (PCT Rule 17.2(a)).</li> <li>* Certified copies not received:</li> </ul>	been received. been received in Application No.	
Applicant has THREE MONTHS FROM THE "MAILING DATE" of noted below. Failure to timely comply will result in ABANDONMI THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	of this communication to file a repi ENT of this application.	ly complying with the requirements
5. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give	tted. Note the attached EXAMINE s reason(s) why the oath or decla	R'S AMENDMENT or NOTICE OF ration is deficient.
<ul> <li>6.  ☐ CORRECTED DRAWINGS ( as "replacement sheets") must (a) ☐ including changes required by the Notice of Draftsperson 1) ☐ hereto or 2) ☐ to Paper No./Mail Date</li> <li>(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date</li> <li>Identifying indicial such as the application number (see 37 CFR 1.6 each sheet. Replacement sheet(s) should be labeled as such in the paper of the depose attached Examiner's comment regarding REQUIREMENT F.</li> </ul>	on's Patent Drawing Review (PTG Amendment / Comment or in the B4(c)) should be written on the draw he header according to 37 CFR 1.12 sit of BIOLOGICAL MATERIAL	Office action of vings in the front (not the back) of 1(d).  . must be submitted. Note the
Attachment(s)  1. ☑ Notice of References Cited (PTO-892)  2. ☑ Notice of Draftperson's Patent Drawing Review (PTO-948)  3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08 Paper No./Mail Date  4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview Summar Paper No./Mail D 7. ☒ Examiner's Amen	Patent Application (PTO-152)  ry (PTO-413), rate dment/Comment  nent of Reasons for Allowance  Chan T. H. Palmer  PHAN T. H. PALMER  PRIMARY EXAMINER  08/02/2005

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## EXAMINER'S AMENDMENT Amot / PMP

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1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows: claims 24-46, 70-92, and 110-124 have been cancelled.

## REASON FOR ALLOWANCE

2. The following is an examiner's statement of reasons for allowance: the claims are allowable over prior art of record, because none of the references in alone or in combination discloses:

## An optoelectronic device on a substrate comprising:

- a waveguide comprising a slab of monocrystalline silicon on the substrate, a layer of dielectric material disposed on the slab, and a strip of polysilicon disposed on the layer of dielectric material;
- a plurality of doped regions in the slab of monocrystalline silicon, where at least first and second doped regions are formed in the slab of monocrystalline silicon, and
- a plurality of electrical contacts, where at least first and second electrical contacts are formed in respective first and second doped regions of the plurality

1.

of doped regions in the slab of monocrystalline silicon, as discloses in claims 1, 47, and 93.

The underlined imitations are critically, since the optoelectronic device is improved: low loss signal, high yields and low fabrication cost and continuous process improvements.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## **CONTACT INFORMATION**

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to PHAN T.H. PALMER whose telephone number is (571) 272-2354. The examiner can normally be reached on Monday to Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, RODNEY B. BOVERNICK can be reached on (571) 272-2344. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

PTHP 08/02/2005

PHAN T. H. PALMER PRIMARY EXAMINER